

<b>Notice of References Cited</b>	Application/Control No. 09/761,240		Applicant(s)/Patent Under Reexamination BAUER ET AL.	
	Examiner Johannes P Mondt		Art Unit 2826	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,668,385	09-1997	Bauer et al.	257/139
*	B	US-5,684,323	11-1997	Tohyama, Shigeru	257/363
	C	US-			
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	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	DE3917769A1 (IDS 7/19/02)	12-1990	Germany	Gerstenmaier et al.	
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**NON-PATENT DOCUMENTS**

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*	U	S.M. Sze, "Physics of Semiconductor Devices", Second Edition, John Wiley & Sons, New York (1981), p. 20-2 (previously made of record, mailed 5/15/2002).
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.